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The Latest Progress in Software Development and Testing

Guest Editor:

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Deadline for manuscript submissions:

closed (15 September 2023)

Message from the Guest Editor

This Special Issue aims to investigate the emerging development and testing approaches for different types of modern software systems including, but not limited to:

- Mobile apps;
- Web apps;
- Al applications;
- Extended reality systems;
- Autonomous driving systems;
- Context-aware systems;
- IoT systems;
- Industry 4.0 systems.

We welcome contributions that will help to answer the following, more specific research questions:

- What are the challenges in modern software development processes and how can they be addressed?
- Which types of software development processes and practices are emerging at the forefront?
- Which methodologies, techniques, environments, frameworks, and tools are emerging for developing, documenting, testing, and validating the software?

Authors are encouraged to submit works related to emerging research topics in different software life-cycle activities, including software requirement analysis and specification, and software design, testing, maintenance, evolution, and quality assurance. Survey studies as well as experimental studies may be submitted to this special Issue.



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Message from the Editor-in-Chief

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